

Page : 1 of 19

Issued date : December 29, 2011 Revised date : January 17, 2012 FCC ID : A98-QOE9653

# **EMI TEST REPORT**

Test Report No.: 32EE0075-HO-C-R1

**Applicant** : **NEC Corporation of America** 

Type of Equipment : Digital Portable Cellular Telephone

Model No. : KMP7N4AC1-3A

FCC ID : A98-QOE9653

Test standard : FCC Part 15 Subpart B: 2011 Class B

Test Result : Complied

- 1. This test report shall not be reproduced in full or partial, without the written approval of UL Japan, Inc.
- 2. The results in this report apply only to the sample tested.
- 3. This sample tested is in compliance with the limits of the above regulation.
- 4. The test results in this test report are traceable to the national or international standards.
- 5. This test report must not be used by the customer to claim product certification, approval, or endorsement by NVLAP, NIST, or any agency of the Federal Government.
- 6. This report is a revised version of 32EE0075-HO-C. 32EE0075-HO-C is replaced with this report.

**Date of test:** December 25, 2011

Representative test engineer:

Katsunori Okai Engineer of WiSE Japan, UL Verification Service

Approved by:

Takahiro Hatakeda Leader of WiSE Japan, UL Verification Service



NVLAP LAB CODE: 200572-0

This laboratory is accredited by the NVLAP LAB CODE 200572-0, U.S.A. The tests reported herein have been performed in accordance with its terms of accreditation. \*As for the range of Accreditation in NVLAP, you may refer to the WEB address,

http://www.ul.com/japan/jpn/pages/services/emc/about/mark1/index.jsp#nvlap

UL Japan, Inc.

Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Page

: 2 of 19

Issued date Revised date FCC ID : December 29, 2011 : January 17, 2012 : A98-QOE9653

CONTENTS	PAGE
SECTION 1: Customer information	3
SECTION 2: Equipment under test (E.U.T.)	
SECTION 3: Test specification, procedures & results	
SECTION 4: Operation of E.U.T. during testing	
SECTION 5: Conducted Emission	
SECTION 6: Radiated Emission	12
APPENDIX 1: Data of EMI test	13
Conducted Emission	
Radiated Emission	
APPENDIX 2: Test instruments	16
APPENDIX 3: Photographs of test setup	17
Conducted Emission	
Radiated Emission	
Worst Case Position (Horizontal: X-axis/ Vertical: X-axis)	19

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Page : 3 of 19

Issued date : December 29, 2011 Revised date : January 17, 2012 FCC ID : A98-QOE9653

### **SECTION 1: Customer information**

Company Name : NEC Corporation of America

Address : Radio Communications Systems Division

6535N. State Highway 161, Irving, TX 75039-2402 USA

Telephone Number : +1 214 262 4241 Facsimile Number : +1 214 262 4225 Contact Person : Sanjay Wadhwa

### **SECTION 2: Equipment under test (E.U.T.)**

### 2.1 Identification of E.U.T.

Type of Equipment : Digital Portable Cellular Telephone

Model No. : KMP7N4AC1-3A

Serial No. : Refer to Section 4, Clause 4.2

Rating : DC 3.8V

Receipt Date of Sample : December 23, 2011

Country of Mass-production : Japan

Condition of EUT : Production prototype

Modification of EUT : No Modification by the test lab

#### 2.2 Product description

Model No: KMP7N4AC1-3A, (referred to as the EUT in this report), is the Digital Portable Cellular Telephone.

### **Head Office EMC Lab.**

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Page : 4 of 19

Issued date : December 29, 2011 Revised date : January 17, 2012 FCC ID : A98-QOE9653

### Radio Specification [1/2]

### Bluetooth (Ver.2.1 + EDR)

Equipment Type	Transceiver
Frequency of Operation	2402-2480MHz
Other Clock Frequency	19.2MHz
Type of Modulation	FHSS
Bandwidth & Channel spacing	1MHz & 1MHz
Antenna Connector Type	Integrated antenna

Low Energy (Ver.4.0)

Equipment Type	Transceiver
Frequency of Operation	2402-2480MHz
Other Clock Frequency	19.2MHz
Bandwidth & Channel spacing	1MHz & 2MHz
Antenna Connector Type	Integrated antenna

#### WLAN (IEEE802.11b/g/n (SISO/HT20))

*** CIEDEO COLOR (SIS OF I	===0))
Equipment Type	Transceiver
Frequency of Operation	2412-2462MHz
Other Clock Frequency	19.2MHz
Type of Modulation	DSSS, OFDM
Antenna Connector Type	Integrated antenna

#### GSM

GBM	
Equipment Type	Transceiver
Frequency of Operation	[Up Link]
	GSM850: 824 – 849MHz
	PCS: 1850 – 1910MHz
	[Down Link]
	GSM850: 869 – 894MHz
	PCS: 1930 – 1990MHz
Other Clock Frequency	19.2MHz
Type of Modulation	GMSK
Channel spacing	200kHz
Antenna Connector Type	Integrated antenna

## UL Japan, Inc. Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Page : 5 of 19

Issued date : December 29, 2011
Revised date : January 17, 2012
FCC ID : A98-QOE9653

#### Radio Specification [2/2]

#### WCDMA

Equipment Type	Transceiver
Frequency of Operation	[Up Link]
	Band V: 824 – 849MHz
	[Down Link]
	Band V: 869 – 894MHz
Other Clock Frequency	19.2MHz
Type of Modulation	HPSK
Channel spacing	5MHz
Antenna Connector Type	Integrated antenna

#### GPS

Equipment Type	Receiver			
Receiver Type Direct Downconversion				
Frequency of Operation	1575.42MHz			
Other Clock Frequency	19.2MHz			
Antenna Connector Type	Integrated antenna			

#### **RFID**

Equipment Type	Transceiver
Frequency of Operation	13.56MHz
Type of Modulation	ASK
Antenna Connector Type	Integrated antenna

# UL Japan, Inc. Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Page : 6 of 19

Issued date : December 29, 2011
Revised date : January 17, 2012
FCC ID : A98-QOE9653

### **SECTION 3: Test specification, procedures & results**

#### 3.1 Test specification

Test Specification : FCC Part 15 Subpart B: 2011, final revised on November 21, 2011 and effective

December 21, 2011

Title : FCC 47CFR Part15 Radio Frequency Device

Subpart B Unintentional Radiators

#### 3.2 Procedures and results

Item	Test Procedure	Limits	Deviation	Worst margin	Result
Conducted emission	FCC: ANSI C63.4: 2003 7. AC powerline conducted emission measurements	Class B	N/A	[QP] 13.8dB 0.20175MHz, L [AV] 11.8dB 0.20175MHz, L	Complied
Radiated emission	FCC: ANSI C63.4: 2003 8. Radiated emission measurements	Class B	N/A	5.6dB 119.999MHz, QP Vertical	Complied
*Note: UL Japan, Inc	l 's EMI Work Procedure 13-EM-W	1 0420.			

#### 3.3 Addition to standard

No addition, exclusion nor deviation has been made from the standard.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Page : 7 of 19

Issued date : December 29, 2011 Revised date : January 17, 2012 FCC ID : A98-QOE9653

#### 3.4 Uncertainty

#### **EMI**

The following uncertainties have been calculated to provide a confidence level of 95% using a coverage factor k=2.

Test room	Conducted emission
(semi-	( <u>+</u> dB)
anechoic	150kHz-30MHz
chamber)	
No.1	3.5dB
No.2	3.6dB
No.3	3.6dB
No.4	3.6dB

Test room	Radiated emission						
(semi-	(3m*)( <u>+</u> dB)				(1m*)( <u>+</u> dB)		$(0.5\text{m*})(\underline{+}\text{dB})$
anechoic	9kHz	30MHz	300MHz	1GHz	10GHz	18GHz	26.5GHz
chamber)	-30MHz	-300MHz	-1GHz	-18GHz	-18GHz	-26.5GHz	-40GHz
No.1	4.2dB	5.0dB	5.1dB	4.7dB	5.7dB	4.4dB	4.3dB
No.2	4.1dB	5.2dB	5.1dB	4.8dB	5.6dB	4.3dB	4.2dB
No.3	4.5dB	5.0dB	5.2dB	4.8dB	5.6dB	4.5dB	4.2dB
No.4	4.7dB	5.2dB	5.2dB	4.8dB	5.6dB	5.1dB	4.2dB

<sup>\*3</sup>m/1m/0.5m = Measurement distance

### Conducted Emission test

The data listed in this test report has enough margin, more than the site margin.

### Radiated emission test(3m)

The data listed in this test report has enough margin, more than the site margin.

**Head Office EMC Lab.** 

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Page : 8 of 19

Issued date : December 29, 2011
Revised date : January 17, 2012
FCC ID : A98-QOE9653

#### 3.5 Test Location

UL Japan, Inc. Head Office EMC Lab. \*NVLAP Lab. code: 200572-0

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Telephone: +81 596 24 8116 Facsimile: +81 596 24 8124

Power
room
-
ation
ation
-
-

<sup>\*</sup> Size of vertical conducting plane (for Conducted Emission test): 2.0 x 2.0m for No.1, No.2, No.3, and No.4 semi-anechoic chambers and No.3 and No.4 shielded rooms.

#### 3.6 Data of EMI, Test instruments, and Test set up

Refer to APPENDIX.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Page : 9 of 19

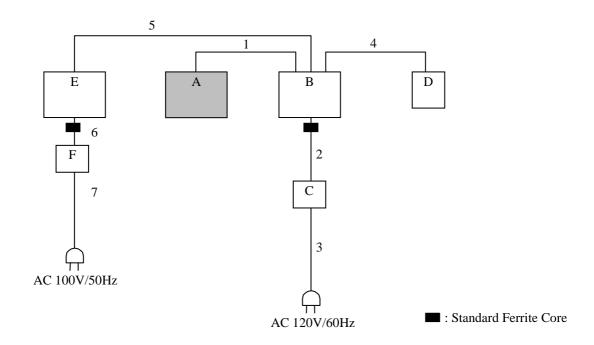
Issued date : December 29, 2011
Revised date : January 17, 2012
FCC ID : A98-QOE9653

# **SECTION 4: Operation of E.U.T. during testing**

#### 4.1 Operating modes

Mode	Remarks
USB Communication mode	*EUT copied the data that was into the Micro SD memory onto laptop PC through the USB cable.

#### 4.2 Configuration and peripherals



<sup>\*</sup>Cabling and setup were taken into consideration and test data was taken under worse case conditions.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

<sup>\*</sup>It was preliminary confirmed that there was no difference in emission level due to a standard ferrite core.

Page : 10 of 19

Issued date : December 29, 2011
Revised date : January 17, 2012
FCC ID : A98-QOE9653

**Description of EUT and Support equipment** 

No.	Item	Model number	Serial number	Manufacturer	Remark
A	Digital Portable	KMP7N4AC1-3A	004401200840235	NEC Corporation of	EUT
	Cellular Telephone			America	
В	Laptop PC	aptop PC 2373T49 L316W54		IBM	DoC
С	AC Adaptor	92P1020	11S92P1020Z1Z9RM6	IBM	DoC
			3A76X		
D	Mouse	MO56UOA	G0100D8Z	DELL	DoC
Е	Printer	Desk Jet 840C	CN0B11C1H2	Hewlett Packard	DoC
F	AC Adapter	C6409-60014	0049R0D	Hewlett Packard	DoC

List of cables used

List O	cabics uscu				
No.	Name	Length (m)	Shi	Remark	
			Cable	Connector	
1	USB Cable	2.0	Shielded	Shielded	-
2	DC Cable	1.0	Unshielded	Unshielded	-
3	AC Cable	1.0	Unshielded	Unshielded	-
4	Mouse Cable	1.8	Shielded	Shielded	-
5	Printer Cable	3.0	Shielded	Shielded	-
6	DC Cable	2.0	Unshielded	Unshielded	-
7	AC Cable	1.0	Unshielded	Unshielded	-

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Page : 11 of 19

Issued date : December 29, 2011
Revised date : January 17, 2012
FCC ID : A98-QOE9653

#### **SECTION 5: Conducted Emission**

### 5.1 Operating environment

Test place : No.4 semi anechoic chamber.

Temperature : See data Humidity : See data

#### 5.2 Test configuration

EUT was placed on a urethane platform of nominal size, 1.0m by 1.5m, raised 0.8m above the conducting ground plane. The rear of tabletop was located 40cm to the vertical conducting plane. The rear of EUT and its peripherals was aligned and flushed with rear of tabletop. All other surfaces of tabletop were at least 80cm from any other grounded conducting surface. EUT was located 80cm from the LISN/AMN and excess AC cable was bundled in center. I/O cables that were connected to the other peripherals were bundled in center. They were folded back and forth forming a bundle 30cm to 40cm long and were hanged at a 40cm height to the ground plane. Each EUT current-carrying power lead, except the ground (safety) lead, was individually connected through a LISN/AMN to the input power source. All unused 50 ohm connectors of the LISN/AMN were resistivity terminated in 50 ohm when not connected to the measuring equipment. Photographs of the set up are shown in Appendix 3.

Frequency range : 0.15 MHz-30MHz

EUT position : Table top EUT operation mode : See Clause 4.1

#### 5.3 Test procedure

The AC Mains Terminal Continuous disturbance Voltage has been measured with the EUT within a semi anechoic chamber. The EUT was connected to a Line Impedance Stabilization Network (LISN)/ Artificial Mains network (AMN). An overview sweep with peak detection has been performed. The measurements have been performed with a quasi-peak detector and if required, with an average detector.

The conducted emission measurements were made with the following detector function of the test receiver.

Detector Type : Quasi-Peak and Average

IF Bandwidth : 9 kHz

#### 5.4 Test result

Summary of the test results: Pass

Date: December 25, 2011 Test engineer: Katsunori Okai

UL Japan, Inc. Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Page : 12 of 19

Issued date : December 29, 2011
Revised date : January 17, 2012
FCC ID : A98-QOE9653

#### **SECTION 6: Radiated Emission**

#### 6.1 Operating environment

Test place : No.4 semi anechoic chamber

Temperature : See data Humidity : See data

#### 6.2 Test configuration

EUT was placed on a urethane platform of nominal size, 1.0m by 1.5m, raised 0.8m above the conducting ground plane. The EUT was set on the center of the tabletop.

Test was made with the antenna positioned in both the horizontal and vertical planes of polarization. The measurement antenna was varied in height above the conducting ground plane to obtain the maximum signal strength. Photographs of the set up are shown in Appendix 3.

#### 6.3 Test conditions

Frequency range : 30MHz-300MHz (Biconical antenna) / 300MHz-1000MHz (Logperiodic antenna)

1000MHz -13000MHz (Horn antenna)

Test distance : 3m EUT position : Table top EUT operation mode : See Clause 4.1

#### 6.4 Test procedure

The height of the measuring antenna varied between 1 and 4m and EUT was rotated a full revolution in order to obtain the maximum value of the electric field intensity.

The measurements were performed for both vertical and horizontal antenna polarization with the Test Receiver, or the Spectrum Analyzer.

The radiated emission measurements were made with the following detector function of the test receiver and the Spectrum analyzer.

Frequency	Below 1GHz	Above 1GHz
Instrument used	Test Receiver	Spectrum Analyzer
IF Bandwidth	QP: BW 120kHz	PK: RBW:1MHz/VBW: 3MHz
		AV *1): RBW:1MHz/VBW:10Hz

<sup>\*1)</sup> When using Spectrum analyzer, the test was made with adjusting span to zero by using peak hold.

- The noise levels were confirmed at each position of X, Y and Z axes of EUT to see the position of maximum noise, and the test was made at the position that has the maximum noise.

#### 6.5 Test result

Summary of the test results: Pass

Date: December 25, 2011 Test engineer: Katsunori Okai

#### UL Japan, Inc. Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

Page : 13 of 19

Issued date : December 29, 2011 Revised date : January 17, 2012 FCC ID : A98-QOE9653

### **APPENDIX 1: Data of EMI test**

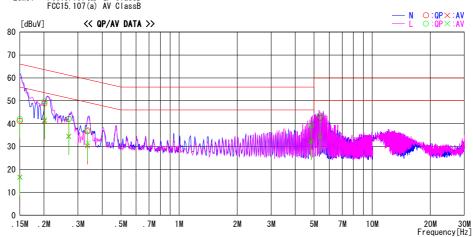
### **Conducted Emission**

### DATA OF CONDUCTED EMISSION TEST

UL Japan, Inc. Head Office EMC Lab. No. 4 Semi Anechoic Chamber Date: 2011/12/25

| Report No. | 32EE0075-H0 | Power | AC 120V / 60Hz | Temp./Humi. | 20deg.C / 35%RH | Engineer | Katsunori Okai

Mode / Remarks : USB Communication LIMIT : FCC15.107(a) QP ClassB FCC15.107(a) AV ClassB



F	Reading	Level			gin						
Frequency	QP	ΑV	Factor	QP	AV	QP	٨V	QP	AV	Phase	Comment
[MHz]	[dBuV]	[dBuV]	[dB]	[dBuV]	[dBuV]	[dBuV]	[dBuV]	[dB]	[dB]		
0. 15000	27.9	3.3		41. 2	16.6	66. 0	56.0		39. 4	N	
0. 20109	35.5	27. 9	13. 3	48. 8	41.2	63. 6	53.6	14. 8	12. 4	N	
0. 26848	28.7	21.2		42. 0	34. 5	61. 2	51.2	19. 2	16. 7	N	
0. 33572	23.3	17. 0		36. 6	30. 3	59. 3	49.3	22.7	19.0	N	
4. 83580	25.5	18.7	13. 7	39. 2	32. 4	56.0	46.0	16.8	13.6	N	
5. 37173	28.6	21.0	13.8	42. 4	34. 8	60. 0	50.0	17. 6	15. 2	N	
0. 15000	28.7	3.4	13. 3	42. 0	16. 7	66. 0	56.0	24. 0	39.3	L	
0. 20175	36.4	28. 4	13. 3	49. 7	41.7	63. 5	53. 5	13.8	11.8	L	
0. 26895	28.8	21.1	13. 3	42. 1	34. 4	61. 2	51.2	19. 1	16.8	L	
0. 33649	23.9	18.3	13. 3	37. 2	31.6	59. 3	49.3	22. 1	17. 7	L	
4. 83440	25.6	18.5	13. 7	39. 3	32. 2	56.0	46.0	16.7	13.8	L	
5. 37171	29.7	20.9	13.8	43. 5	34. 7	60.0	50.0	16.5	15.3	L	

\*The limit is rounded down to one decimal place.

\*The test result is rounded off to one or two decimal places, so some differences might be observed.

# UL Japan, Inc.

**Head Office EMC Lab.** 

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

: 32EE0075-HO-C-R1 Test report No.

Page : 14 of 19

**Issued date** : December 29, 2011 : January 17, 2012 Revised date FCC ID : A98-QOE9653

### **Radiated Emission**

### DATA OF RADIATED EMISSION TEST

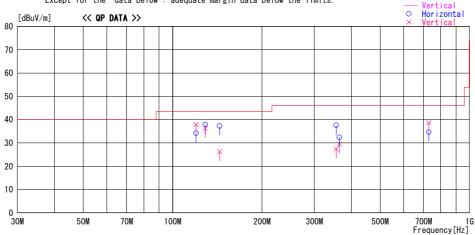
Head Office EMC Lab. No.4 Semi Anechoic Chamber Date : 2011/12/25

Report No. Power Temp./Humi. 32EE0075-H0 AC 120V / 60Hz 20deg.C / 35% RH Katsunori Okai

Mode / Remarks : USB Communication

LIMIT : FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:PK Except for the data below : adequate margin data below the limits.

Horizontal



Frequency	Reading	DET	Antenna Factor	Loss& Gain	Level	Angle	Height	Polar.	Limit	Margin	Comment
[MHz]	[dBuV]	DLI	[dB/m]	[dB]	[dBuV/m]	[Deg]	[cm]	TOTAL.	[dBuV/m]	[dB]	Oominort
119. 999	45. 2	QP	12. 9	-23. 9	34. 2	121	140	Hori.	43. 5	9.3	
119. 999		QP	12. 9	-23. 9	37. 9	190		Vert.	43. 5	5. 6	
128. 851	46. 4	QP	13. 7	-23. 8	36. 3	340	100	Vert.	43. 5	7. 2	
128. 852	47. 9	QP	13. 7	-23. 8	37. 8	268	167	Hori.	43. 5	5. 7	
143. 992	35.0	QP	14. 8	-23. 6	26. 2	188	100	Vert.	43. 5	17. 3	
143. 992	46. 1	QP	14. 8	-23. 6	37. 3	245	223	Hori.	43. 5	6. 2	
355. 321	32. 4	QP	17. 0	-22.0	27. 4	291	100	Vert.	46. 0	18. 6	
355. 521	42. 6	QP	17. 0	-22.0	37. 6	10	100	Hori.	46. 0	8. 4	
364. 503	37. 2	QP	17. 1	-21.9	32. 4	27	100	Hori.	46. 0	13.6	
364. 504	34. 3	QP	17. 1	-21.9	29. 5	201	100	Vert.	46. 0	16.5	
729. 007	32.0	QP	22. 5	-19.8	34. 7	66	100	Hori.	46. 0	11.3	
729. 007	36.0	QP	22. 5	-19.8	38. 7	98	100	Vert.	46. 0	7.3	

CHART:WITH FACTOR ANT TYPE: -30MHz:LOOP, 30-300MHz:BICONICAL, 300MHz-1000MHz:LOGPERIODIC, 1000MHz-:HORN CALCULATION:RESULT = READING + ANT FACTOR + LOSS (CABLE+ATTEN.) - GAIN (AMP)

\*The limit is rounded down to one decimal place.

\*The test result is rounded off to one or two decimal places, so some differences might be observed.

# UL Japan, Inc.

#### Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

: 32EE0075-HO-C-R1 Test report No.

Page : 15 of 19

Issued date : December 29, 2011 : January 17, 2012 Revised date FCC ID : A98-QOE9653

### **Radiated Emission**

### DATA OF RADIATED EMISSION TEST

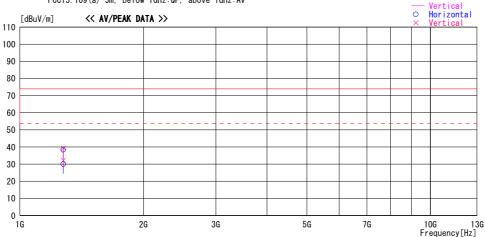
Head Office EMC Lab. No.4 Semi Anechoic Chamber Date : 2011/12/25

Report No. Power Temp./Humi. 32EE0075-H0 AC 120V / 60Hz 20deg.C / 35% RH Katsunori Okai

Mode / Remarks : USB Communication

FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:PK FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:AV

— Horizontal



Frequency	Reading	DET	Antenna Factor	Loss& Gain	Level	Angle	Height	Polar.	Limit	Margin	Comment
[MHz]	[dBuV]	DLI	[dB/m]	[dB]	[dBuV/m]	[Deg]	[cm]	rolal.	[dBuV/m]	[dB]	COMMISSION
1275. 766		PK	24. 7	-32. 2	39. 3			Vert.	73. 9		
1275. 766		AV	24. 7	-32. 2	32. 2				53. 9		
1275. 767	45. 8	PK	24. 7	-32. 2	38. 3	240	100	Hori.	73. 9	35.6	
1275. 767	37. 5	AV	24. 7	-32. 2	30. 0	240	100	Hori.	53. 9	23. 9	

\*The limit is rounded down to one decimal place.

\*The test result is rounded off to one or two decimal places, so some differences might be observed.

# UL Japan, Inc.

### Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

: +81 596 24 8116 **Telephone** Facsimile : +81 596 24 8124

Page : 16 of 19

Issued date : December 29, 2011
Revised date : January 17, 2012
FCC ID : A98-QOE9653

### **APPENDIX 2: Test instruments**

**EMI** test equipment

EMI test eq Control No.	Instrument	Manufacturer	Model No	Serial No	Test Item	Calibration Date	Expiration date of the calibration
MAEC-04	Semi Anechoic Chamber(NSA)	TDK	Semi Anechoic Chamber 3m	DA-10005	RE/CE	2011/03/01	2012/03/31
MOS-15	Thermo-Hygrometer	Custom	CTH-180	-	RE/CE	2011/02/23	2012/02/29
MJM-07	Measure	PROMART	SEN1955	-	RE/CE	-	-
COTS-MEMI	EMI measurement program	TSJ	TEPTO-DV	-	RE/CE	-	-
MSA-04	Spectrum Analyzer	Agilent	E4448A	US44300523	RE/CE	2011/04/08	2012/04/30
MTR-07	Test Receiver	Rohde & Schwarz	ESCI	100635	RE/CE	2011/10/19	2012/10/31
MBA-05	Biconical Antenna	Schwarzbeck	BBA9106	1302	RE	2011/11/16	2012/11/30
MLA-08	Logperiodic Antenna	Schwarzbeck	UKLP9140-A	N/A	RE	2011/11/16	2012/11/30
MCC-50	Coaxial Cable	UL Japan	-	-	RE	2011/03/25	2012/03/31
MAT-51	Attenuator(6dB)	Weinschel	2	AS3557	RE	2011/01/14	2012/01/31
MPA-14	Pre Amplifier	SONOMA INSTRUMENT	310	260833	RE	2011/03/04	2012/03/31
MHA-21	Horn Antenna 1-18GHz	Schwarzbeck	BBHA9120D	9120D-557	RE	2011/08/11	2012/08/31
MCC-56	Microwave Cable	Suhner	SUCOFLEX104	270875/4(1m) / 284655(5m)	RE	2011/03/02	2012/03/31
MPA-12	MicroWave System Amplifier	Agilent	83017A	MY39500780	RE	2011/03/10	2012/03/31
MLS-06	LISN(AMN)	Schwarzbeck	NSLK8127	8127363	CE	2011/02/20	2012/02/29
MLS-07	LISN(AMN)	Schwarzbeck	NSLK8127	8127364	CE	2011/02/22	2012/02/29
MTA-31	Terminator	TME	CT-01	-	CE	2011/01/05	2012/01/31
MAT-67	Attenuator(13dB)	JFW Industries, Inc.	50FP-013H2 N	-	CE	2011/02/22	2012/02/29
MCC-113	Coaxial cable	Fujikura/Suhner/TSJ	5D- 2W(10m)/SFM141( 5m)/421- 010(1m)/sucoform1 41-PE(1m)/RFM- E121(Switcher)	-/04178	CE	2011/07/04	2012/07/31

The expiration date of the calibration is the end of the expired month.

All equipment is calibrated with valid calibrations. Each measurement data is traceable to the national or international standards.

As for some calibrations performed after the tested dates, those test equipment have been controlled by means of an unbroken chains of calibrations.

#### **Test Item:**

**CE: Conducted emission RE: Radiated emission** 

UL Japan, Inc. Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN